Application/Control No.	Applicant(s)/Patent under Reexamination	
10/563,441	RIETJENS ET AL.	
Examiner	Art Unit	
Louis K. Huynh	3721	

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Class	Subclass	Date	Examiner
493	59 227 228 240	5/14/2007	LH

Class	Subclass	Date	Examiner
493	59 227 228 240 355	5/14/2007	LH
53	412 133.8	5/14/2007	LH
219	121.67	5/14/2007	LH
219	121,69	5/14/2007	LH
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